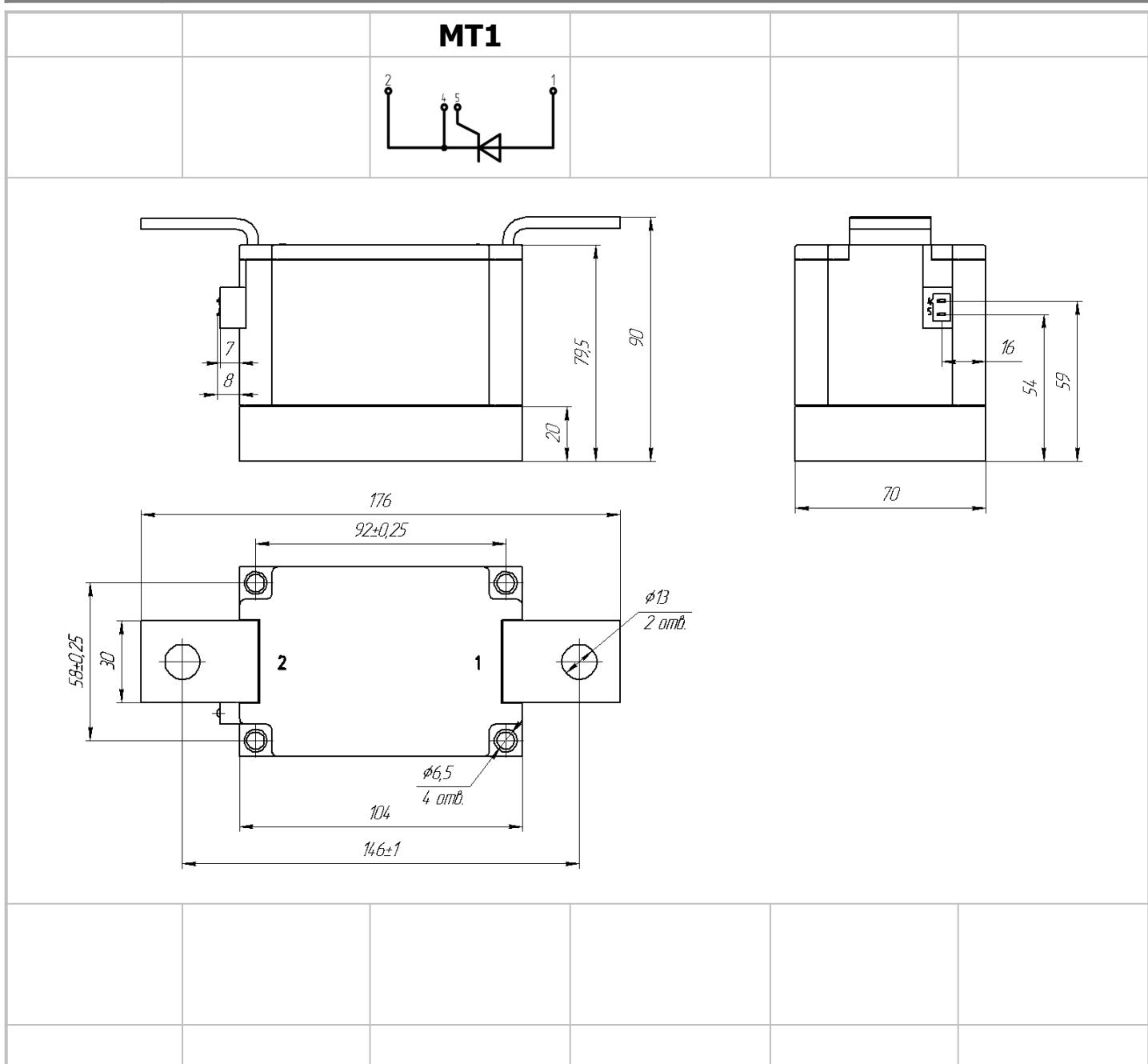




Electrically isolated base plate  
Industrial standard package  
Simplified mechanical design, rapid assembly  
Pressure contact

**Single Thyristor Module  
For Phase Control  
MT1-800-18-E**

Mean on-state current	I <sub>TAV</sub>	800 A						
Repetitive peak off-state voltage	V <sub>DRM</sub>	1000...1800 V						
Repetitive peak reverse voltage	V <sub>RRM</sub>							
Turn-off time	t <sub>q</sub>	250 $\mu$ s						
V <sub>DRM</sub> , V <sub>RRM</sub> , V	1000	1100	1200	1300	1400	1500	1600	1800
Voltage code	10	11	12	13	14	15	16	18
T <sub>j</sub> , °C	-40...+130							



## MAXIMUM ALLOWABLE RATINGS

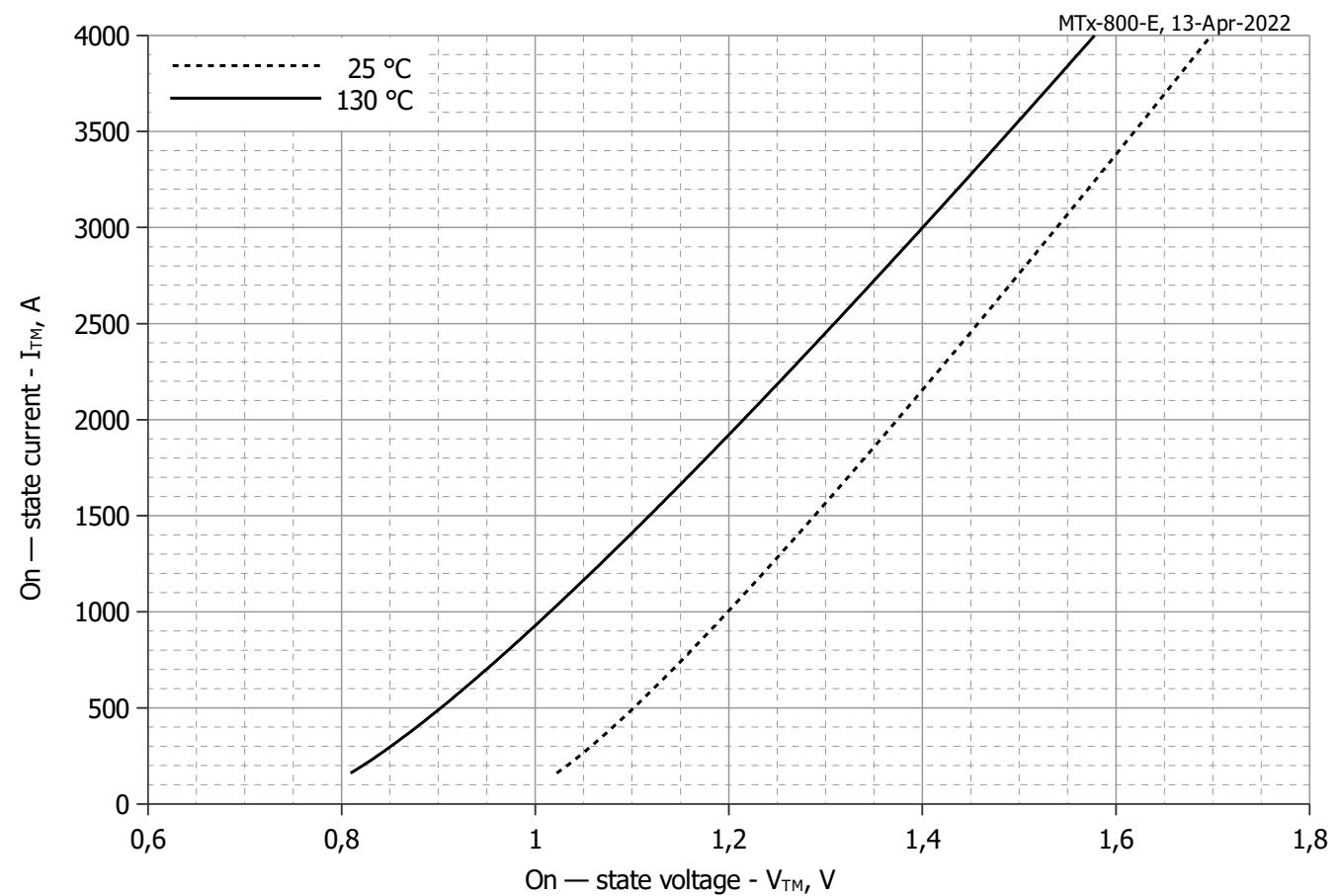
Symbols and parameters		Units	Values	Test conditions	
<b>ON-STATE</b>					
$I_{TAV}$	Maximum allowable mean on-state current	A	800 901	$T_c=91 \text{ }^\circ\text{C};$ $T_c=85 \text{ }^\circ\text{C};$ 180° half-sine wave; 50 Hz	
$I_{TRMS}$	RMS on-state current	A	1256	$T_c=91 \text{ }^\circ\text{C};$ 180° half-sine wave; 50 Hz	
$I_{TSM}$	Surge on-state current	kA	42.0 48.0	$T_j=T_{j \max}$ $T_j=25 \text{ }^\circ\text{C}$	180° half-sine wave; $t_p=10 \text{ ms}$ ; single pulse; $V_D=V_R=0 \text{ V}$ ; Gate pulse: $I_G=2 \text{ A}$ ; $V_G=20 \text{ V}$ ; $t_{GP}=500 \mu\text{s}$ ; $di_G/dt=1 \text{ A}/\mu\text{s}$
			44.0 51.0	$T_j=T_{j \max}$ $T_j=25 \text{ }^\circ\text{C}$	180° half-sine wave; $t_p=8.3 \text{ ms}$ ; single pulse; $V_D=V_R=0 \text{ V}$ ; Gate pulse: $I_G=2 \text{ A}$ ; $V_G=20 \text{ V}$ ; $t_{GP}=500 \mu\text{s}$ ; $di_G/dt=1 \text{ A}/\mu\text{s}$
$I^2t$	Safety factor	$\text{A}^2 \cdot 10^3$	8800 11500	$T_j=T_{j \max}$ $T_j=25 \text{ }^\circ\text{C}$	180° half-sine wave; $t_p=10 \text{ ms}$ ; single pulse; $V_D=V_R=0 \text{ V}$ ; Gate pulse: $I_G=2 \text{ A}$ ; $V_G=20 \text{ V}$ ; $t_{GP}=500 \mu\text{s}$ ; $di_G/dt=1 \text{ A}/\mu\text{s}$
			8000 10700	$T_j=T_{j \max}$ $T_j=25 \text{ }^\circ\text{C}$	180° half-sine wave; $t_p=8.3 \text{ ms}$ ; single pulse; $V_D=V_R=0 \text{ V}$ ; Gate pulse: $I_G=2 \text{ A}$ ; $V_G=20 \text{ V}$ ; $t_{GP}=500 \mu\text{s}$ ; $di_G/dt=1 \text{ A}/\mu\text{s}$
<b>BLOCKING</b>					
$V_{DRM}, V_{RRM}$	Repetitive peak off-state and Repetitive peak reverse voltages	V	1000...1800	$T_{j \min} < T_j < T_{j \max};$ 180° half-sine wave; 50 Hz; Gate open	
$V_{DSM}, V_{RSM}$	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	1100...1900	$T_{j \min} < T_j < T_{j \max};$ 180° half-sine wave; single pulse; Gate open	
$V_D, V_R$	Direct off-state and Direct reverse voltages	V	$0.6 \cdot V_{DRM}$ $0.6 \cdot V_{RRM}$	$T_j=T_{j \max};$ Gate open	
<b>TRIGGERING</b>					
$I_{FGM}$	Peak forward gate current	A	8	$T_j=T_{j \max}$	
$V_{RGM}$	Peak reverse gate voltage	V	5		
$P_G$	Gate power dissipation	W	4	$T_j=T_{j \max}$ for DC gate current	
<b>SWITCHING</b>					
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive ( $f=1 \text{ Hz}$ )	$\text{A}/\mu\text{s}$	630	$T_j=T_{j \max}; V_D=0.67 \cdot V_{DRM}; I_{TM}=2200 \text{ A};$ Gate pulse: $I_G=2 \text{ A}$ ; $V_G=20 \text{ V}$ ; $t_{GP}=50 \mu\text{s}$ ; $di_G/dt=2 \text{ A}/\mu\text{s}$	
<b>THERMAL</b>					
$T_{stg}$	Storage temperature	$^\circ\text{C}$	-40...+50		
$T_j$	Operating junction temperature	$^\circ\text{C}$	-40...+130		
$T_{c op}$	Operating temperature	$^\circ\text{C}$	-40...+125		
<b>MECHANICAL</b>					
a	Acceleration under vibration	$\text{m/s}^2$	50		

## CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions			
<b>ON-STATE</b>							
V <sub>TM</sub>	Peak on-state voltage, max	V	1.45	T <sub>j</sub> =25 °C; I <sub>TM</sub> =2500 A			
V <sub>T(TO)</sub>	On-state threshold voltage, max	V	0.834	T <sub>j</sub> =T <sub>j</sub> max;			
r <sub>T</sub>	On-state slope resistance, max	mΩ	0.187	0.5 π I <sub>TAV</sub> < I <sub>T</sub> < 1.5 π I <sub>TAV</sub>			
I <sub>L</sub>	Latching current, max	mA	1500	T <sub>j</sub> =25 °C; V <sub>D</sub> =12 V; Gate pulse: I <sub>G</sub> =I <sub>FGM</sub> ; V <sub>G</sub> =20 V; t <sub>GP</sub> =500 μs; di <sub>G</sub> /dt=1 A/μs			
I <sub>H</sub>	Holding current, max	mA	300	T <sub>j</sub> =25 °C; V <sub>D</sub> =12 V; Gate open			
<b>BLOCKING</b>							
I <sub>DRM</sub> , I <sub>RRM</sub>	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	150 4.00	T <sub>j</sub> =T <sub>j</sub> max T <sub>j</sub> = 25 °C	V <sub>D</sub> =V <sub>DRM</sub> ; V <sub>R</sub> =V <sub>RRM</sub>		
(dv <sub>D</sub> /dt) <sub>crit</sub>	Critical rate of rise of off-state voltage <sup>1)</sup> , min	V/μs	200, 320, 500, 1000, 1600, 2000, 2500	T <sub>j</sub> =T <sub>j</sub> max; V <sub>D</sub> =0.67·V <sub>DRM</sub> ; Gate open			
<b>TRIGGERING</b>							
V <sub>GT</sub>	Gate trigger direct voltage, max	V	3.00 2.50 1.50	T <sub>j</sub> = T <sub>j</sub> min T <sub>j</sub> =25 °C T <sub>j</sub> = T <sub>j</sub> max	V <sub>D</sub> =12 V; I <sub>D</sub> =3 A; Direct gate current		
I <sub>GT</sub>	Gate trigger direct current, max	mA	400 250 150	T <sub>j</sub> = T <sub>j</sub> min T <sub>j</sub> = 25 °C T <sub>j</sub> = T <sub>j</sub> max			
V <sub>GD</sub>	Gate non-trigger direct voltage, min	V	0.50	T <sub>j</sub> =T <sub>j</sub> max; V <sub>D</sub> =0.67·V <sub>DRM</sub> ;			
I <sub>GD</sub>	Gate non-trigger direct current, min	mA	80.00	Direct gate current			
<b>SWITCHING</b>							
t <sub>gd</sub>	Delay time, max	μs	0.90	T <sub>j</sub> =25 °C; V <sub>D</sub> =1000 V; I <sub>TM</sub> =I <sub>TAV</sub> ; di/dt=200 A/μs;	Gate pulse: I <sub>G</sub> =2 A; V <sub>G</sub> =20 V; t <sub>GP</sub> =50 μs; di <sub>G</sub> /dt=2 A/μs		
t <sub>gt</sub>	Turn-on time, max	μs	2.00	di <sub>R</sub> /dt=50 V/μs; T <sub>j</sub> =T <sub>j</sub> max; I <sub>TM</sub> = I <sub>TAV</sub> ;			
t <sub>q</sub>	Turn-off time <sup>2)</sup> , max	μs	250	di <sub>R</sub> /dt=-10 A/μs; V <sub>R</sub> =100 V; V <sub>D</sub> =0.67·V <sub>DRM</sub>			
Q <sub>rr</sub>	Total recovered charge, max	μC	3140	T <sub>j</sub> =T <sub>j</sub> max; I <sub>TM</sub> =I <sub>TAV</sub> ;	di <sub>R</sub> /dt=-10 A/μs; V <sub>R</sub> =100 V		
t <sub>rr</sub>	Reverse recovery time, max	μs	33	di <sub>R</sub> /dt=-10 A/μs;			
I <sub>rr</sub>	Reverse recovery current, max	A	190	V <sub>R</sub> =100 V			
<b>THERMAL</b>							
R <sub>thjc</sub>	Thermal resistance, junction to case	per module		180° half-sine wave, 50 Hz			
R <sub>thch</sub>	Thermal resistance, case to heatsink	per module					
<b>INSULATION</b>							
V <sub>ISOL</sub>	Insulation test voltage	kV	3.00	Sine wave, 50 Hz;	t=60 sec t=1 sec		
			3.60	RMS			
<b>MECHANICAL</b>							
M <sub>1</sub>	Mounting torque (M6) <sup>3)</sup>	Nm	6.00	Tolerance ± 15%			
M <sub>2</sub>	Terminal connection torque (M12) <sup>3)</sup>	Nm	18.00	Tolerance ± 15%			
m	Weight, max	g	2250				

PART NUMBERING GUIDE								NOTES																							
MT 1 - 800 - 18 - A2 M2 - E - N								1) Critical rate of rise of off-state voltage																							
1 2 3 4 5 6 7 8								<table border="1"> <thead> <tr> <th>Symbol of Group (dv<sub>D</sub>/dt)<sub>crit</sub>, V/μs</th> <th>P2</th> <th>K2</th> <th>E2</th> <th>A2</th> <th>T1</th> <th>P1</th> <th>M1</th> </tr> </thead> <tbody> <tr> <td>200</td> <td>320</td> <td>500</td> <td>1000</td> <td>1600</td> <td>2000</td> <td>2500</td> <td></td> </tr> </tbody> </table>								Symbol of Group (dv <sub>D</sub> /dt) <sub>crit</sub> , V/μs	P2	K2	E2	A2	T1	P1	M1	200	320	500	1000	1600	2000	2500	
Symbol of Group (dv <sub>D</sub> /dt) <sub>crit</sub> , V/μs	P2	K2	E2	A2	T1	P1	M1																								
200	320	500	1000	1600	2000	2500																									
1. MT - Thyristor module 2. Circuit Schematic 3. Average On-state Current, A 4. Voltage Code 5. Critical rate of rise of off-state voltage 6. Group of turn-off time (dv <sub>D</sub> /dt=50 V/μs) 7. Package Type (M.E) 8. Ambient Conditions: N – Normal								2) Turn-off time (dv <sub>D</sub> /dt=50 V/μs)																							
								<table border="1"> <thead> <tr> <th>Symbol of Group t<sub>q</sub>, μs</th> <th>M2</th> </tr> </thead> <tbody> <tr> <td></td> <td>250</td> </tr> </tbody> </table>							Symbol of Group t <sub>q</sub> , μs	M2		250													
Symbol of Group t <sub>q</sub> , μs	M2																														
	250																														
								3) The screws must be lubricated																							

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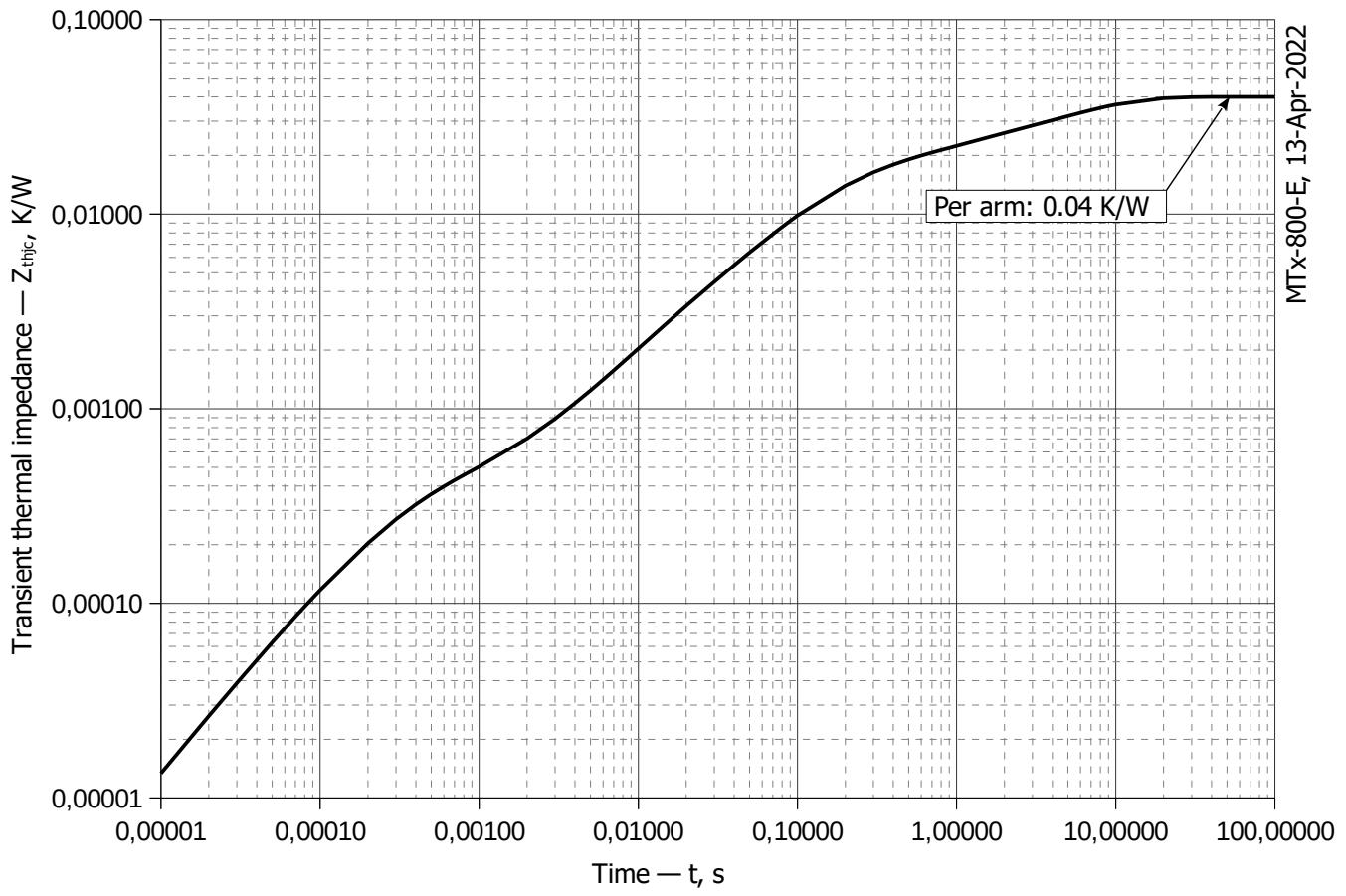
**Fig 1 – On-state characteristics of Limit device**

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients for max curves	
	$T_j = 25^\circ\text{C}$	$T_j = T_{j,\max}$
<b>A</b>	0.93815531	0.72539983
<b>B</b>	0.00013321	0.00013743
<b>C</b>	0.00505674	0.00041170
<b>D</b>	0.00293182	0.00473380

**On-state characteristic model (see Fig. 1)**



**Fig 2 – Transient thermal impedance  $Z_{thjc}$  vs. time  $t$**

Analytical function for Transient thermal impedance junction to case  $Z_{thjc}$  for DC:

$$Z_{thjc} = \sum_{i=1}^n R_i \left( 1 - e^{-\frac{t}{\tau_i}} \right)$$

Where  $i = 1$  to  $n$ ,  $n$  is the number of terms in the series.

$t$  = Duration of heating pulse in seconds.

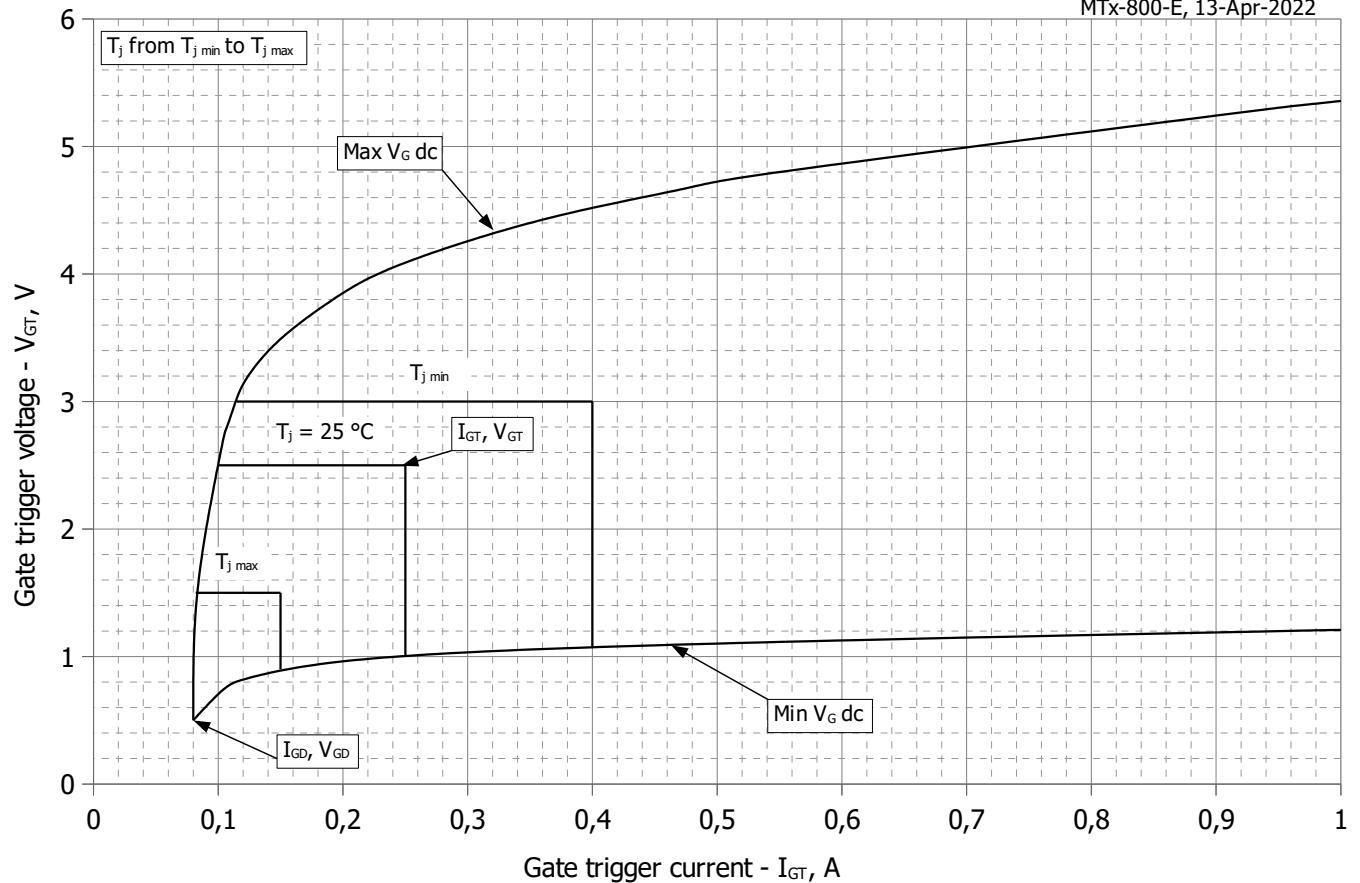
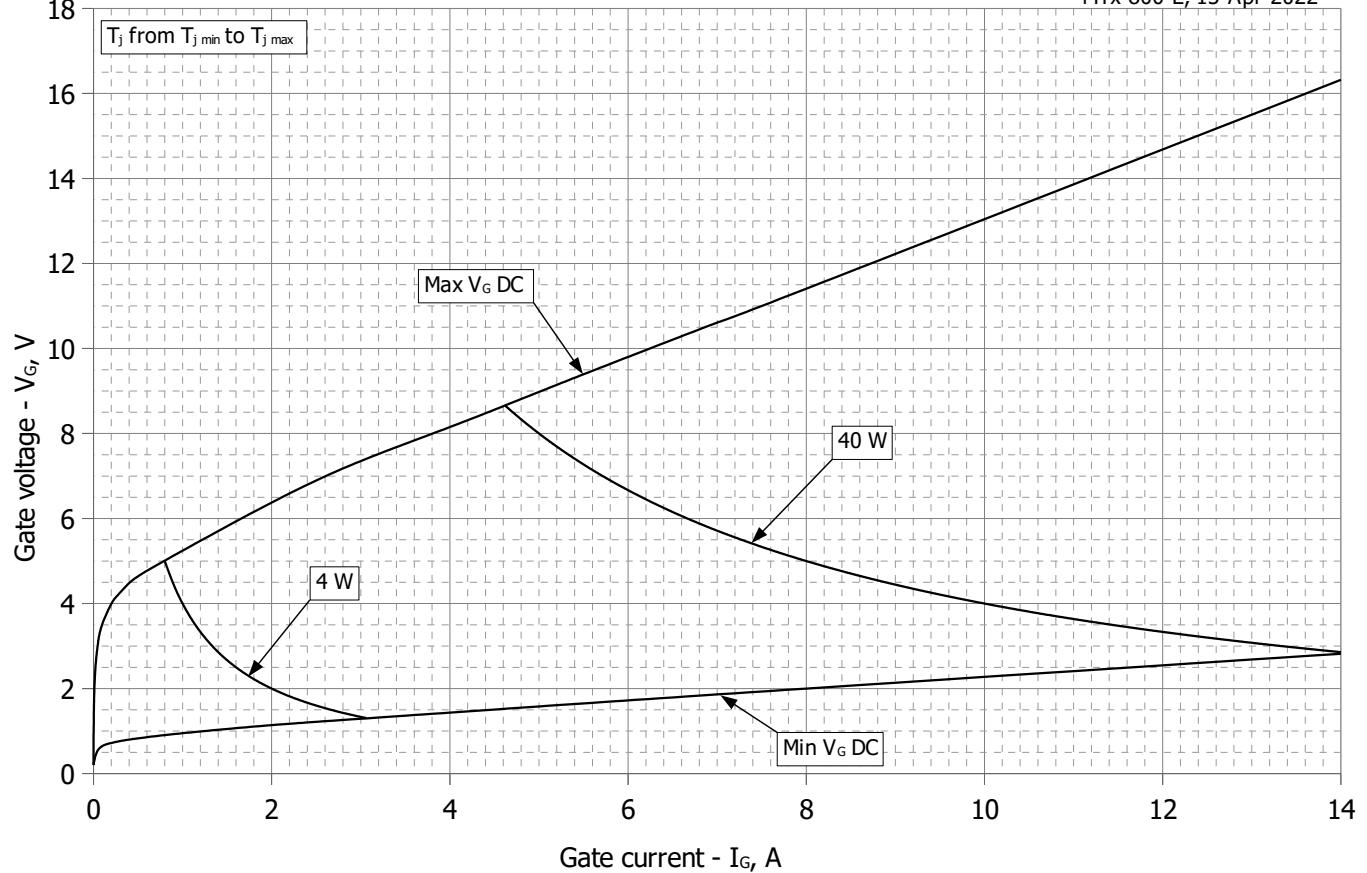
$Z_{thjc}$  = Thermal resistance at time  $t$ .

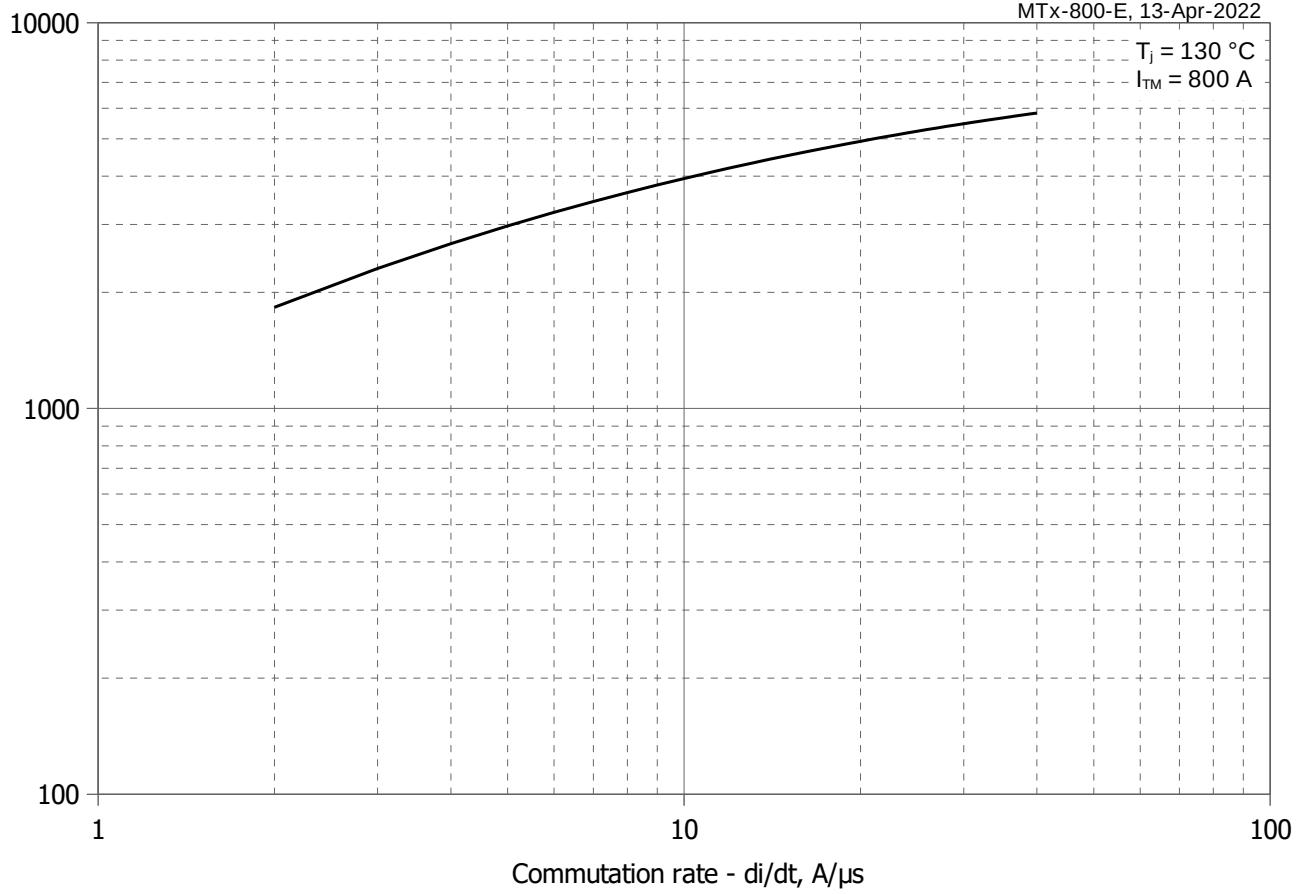
$R_i$  = Amplitude of  $p_{th}$  term.

$\tau_i$  = Time constant of  $r_{th}$  term.

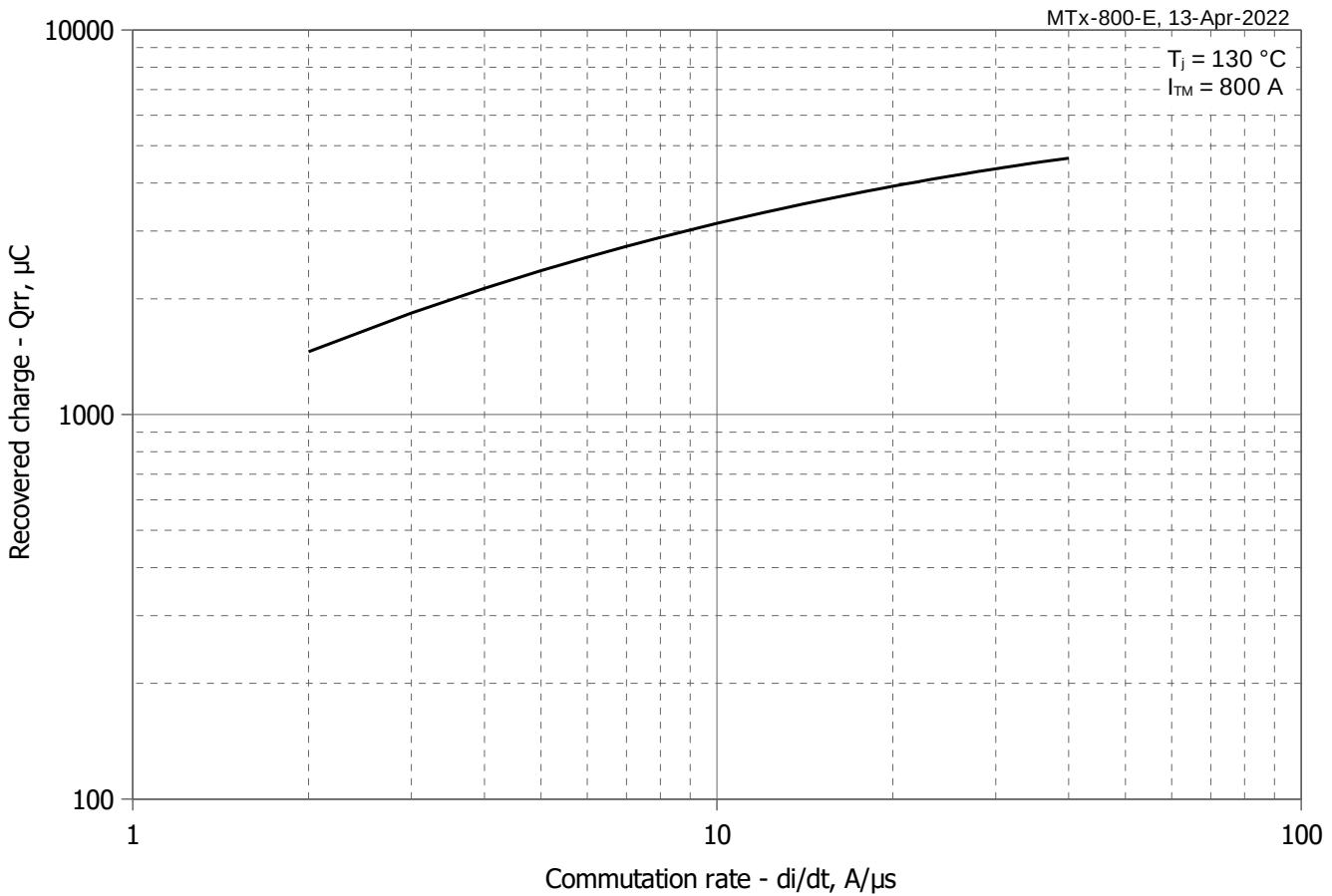
i	1	2	3	4	5	6
$R_i$ , K/W	0.02251	0.005931	0.009502	0.004252	0.001006	0.0003132
$\tau_i$ , s	5.887	0.7389	0.1616	0.08215	0.01267	0.0002712

**Transient thermal impedance junction to case  $Z_{thjc}$  model (see Fig. 2)**

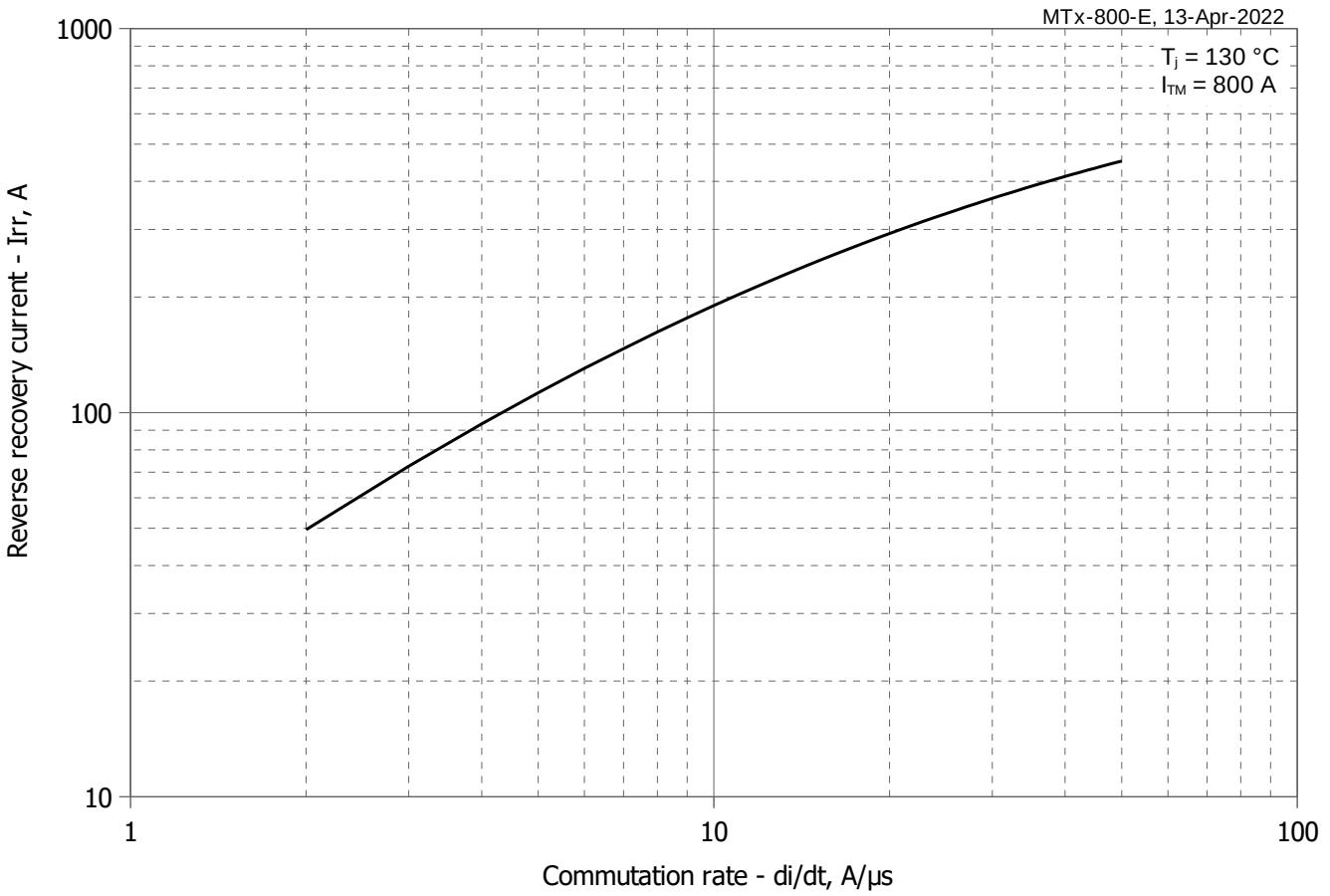
**Fig 3 – Gate characteristics – Trigger limits****Fig 4 - Gate characteristics – Power curves**



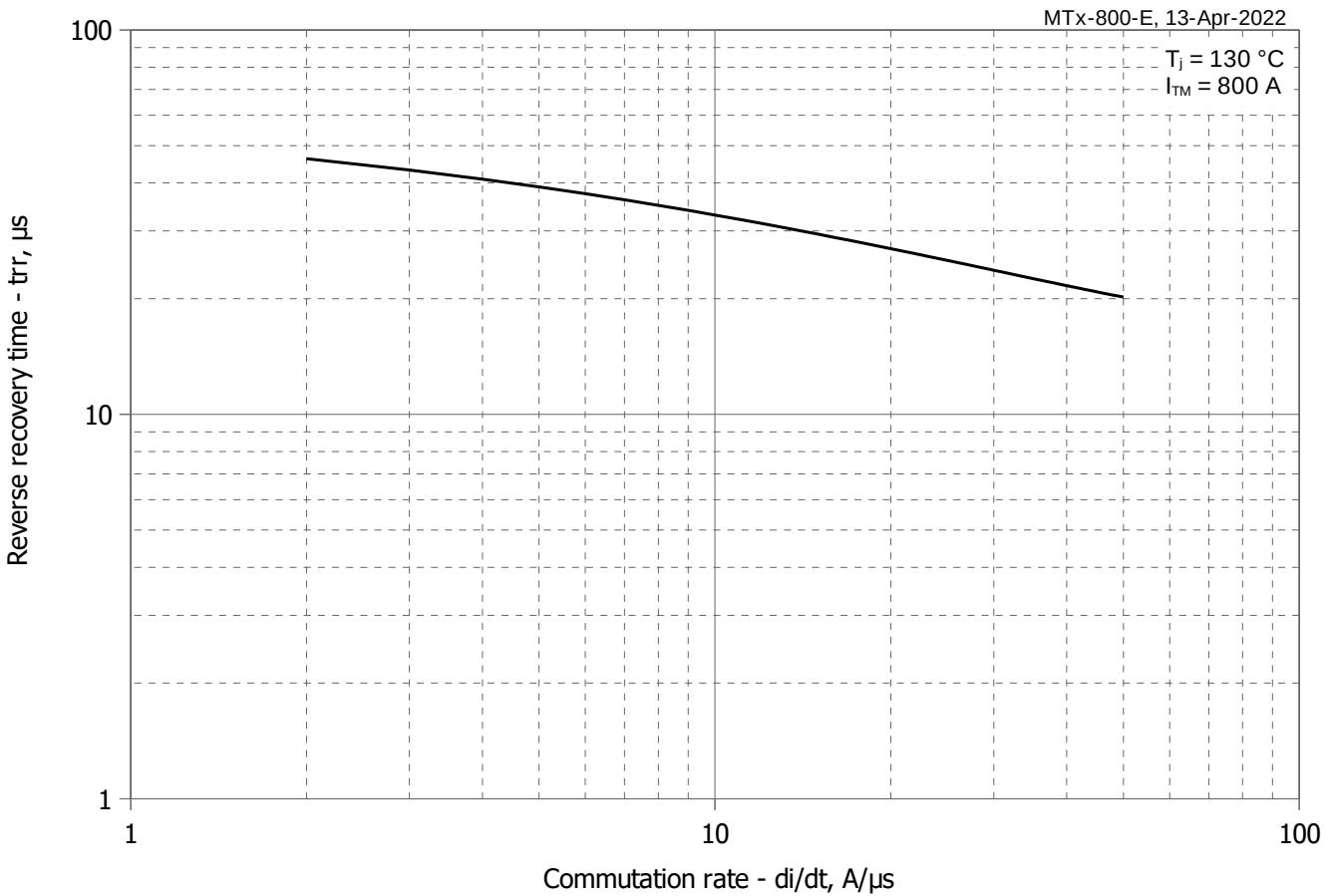
**Fig 5 – Maximum recovered charge  $Q_{rr-i}$  (integral) vs. commutation rate  $di_R/dt$**



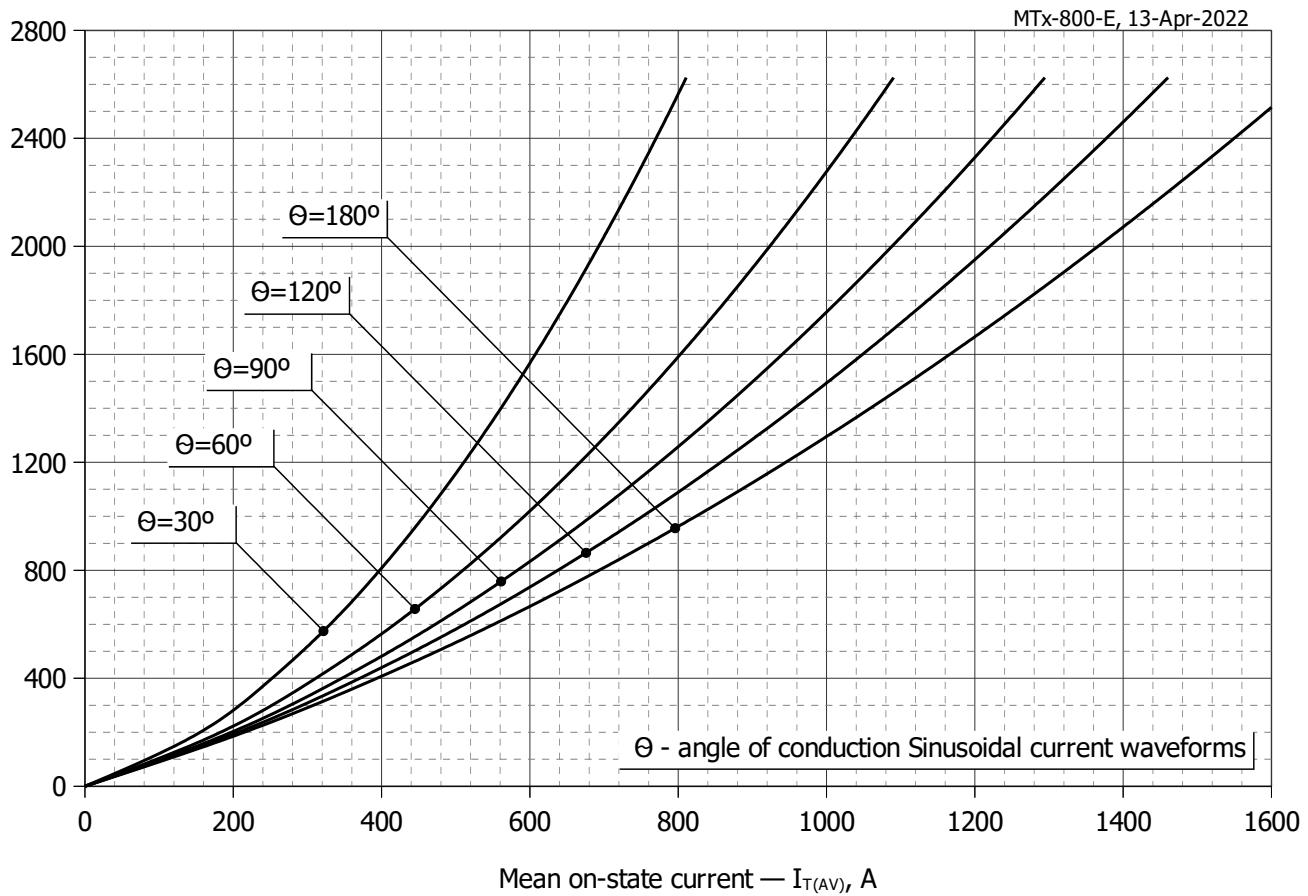
**Fig 6 – Maximum recovered charge  $Q_{rr}$  vs. commutation rate  $di_R/dt$  (25% chord)**



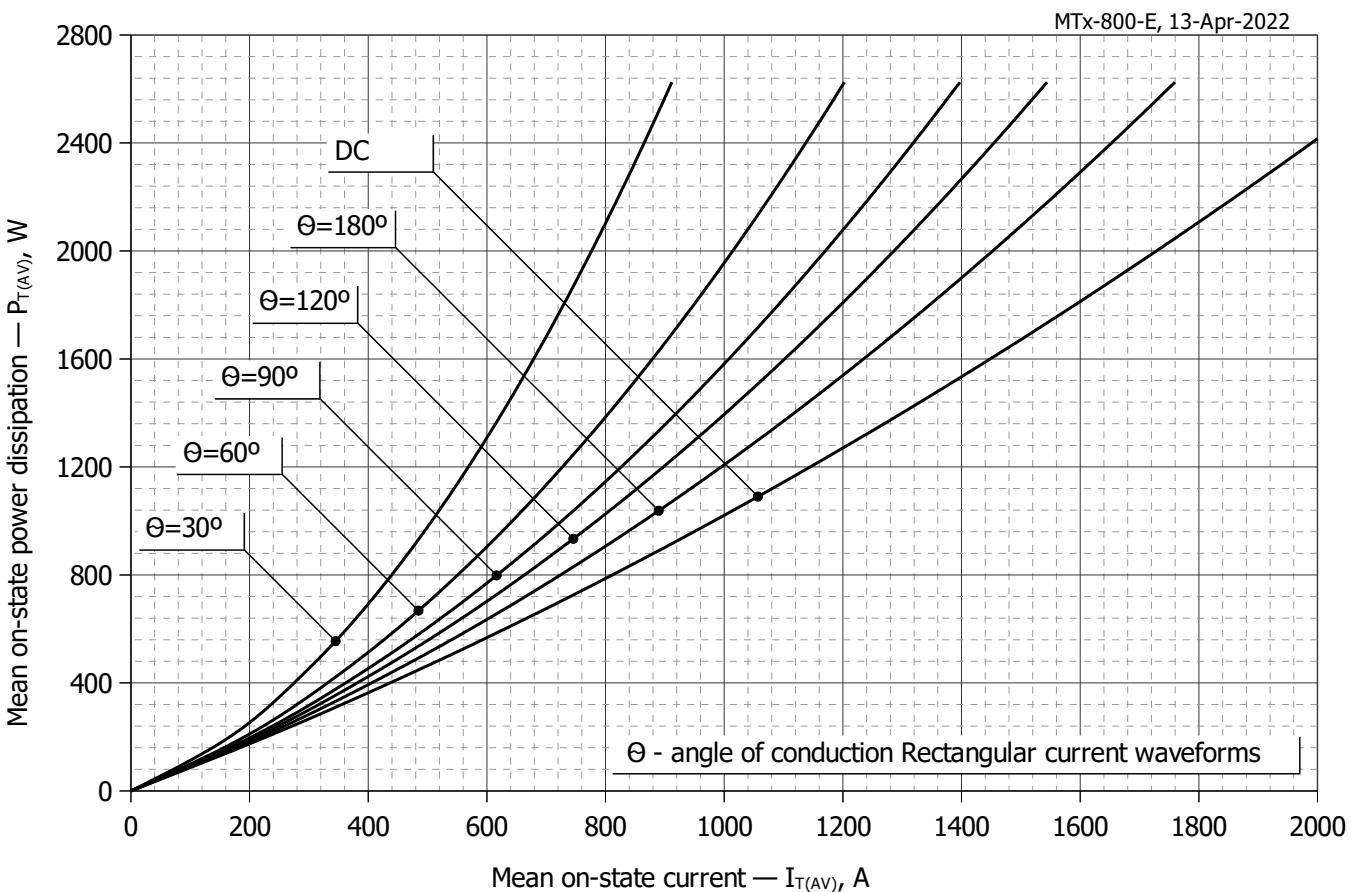
**Fig 7 – Maximum reverse recovery current  $I_{rr}$  vs. commutation rate  $di_R/dt$**



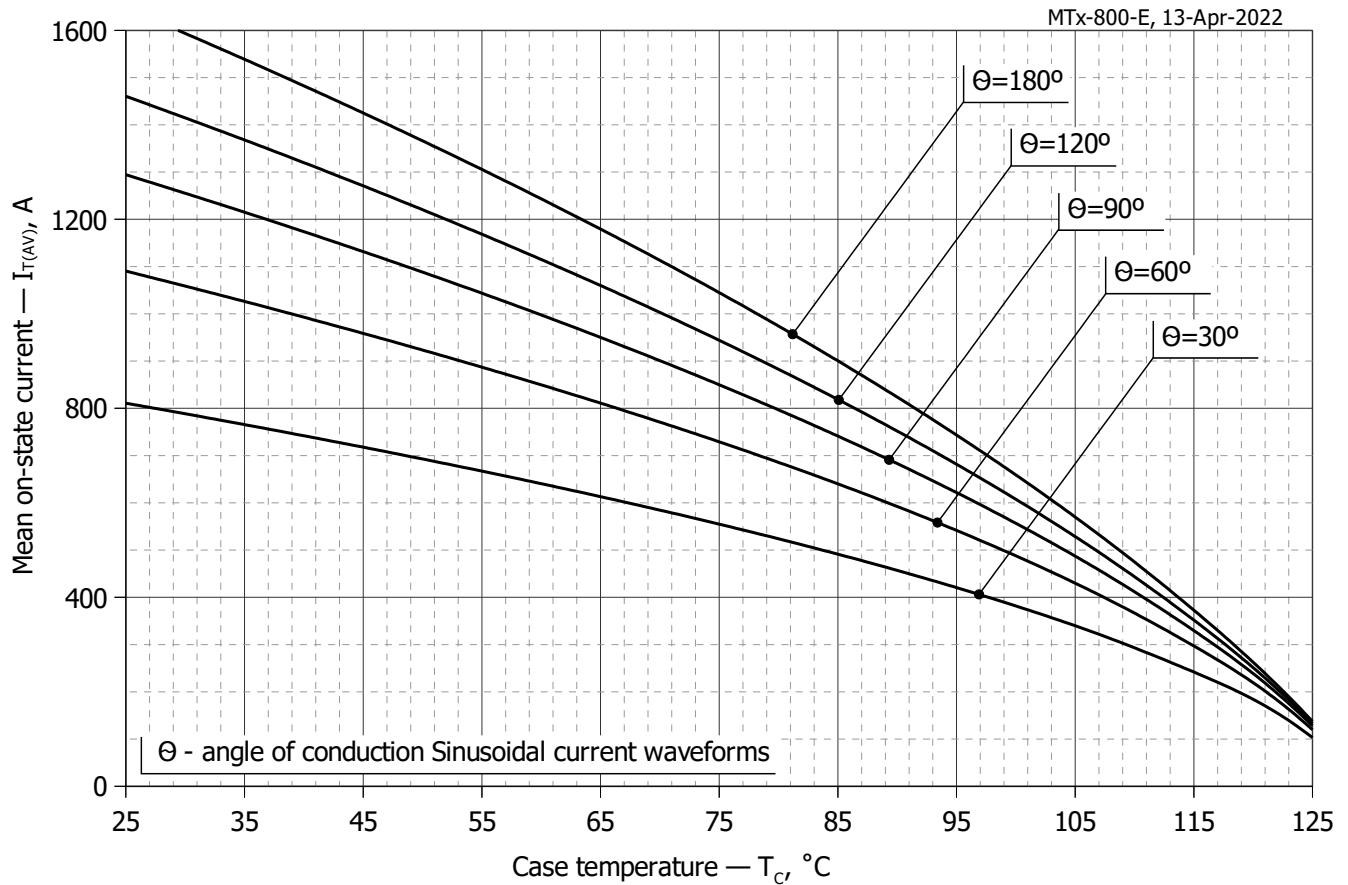
**Fig 8 – Maximum recovery time  $t_{rr}$  vs. commutation rate  $di_R/dt$  (25% chord)**



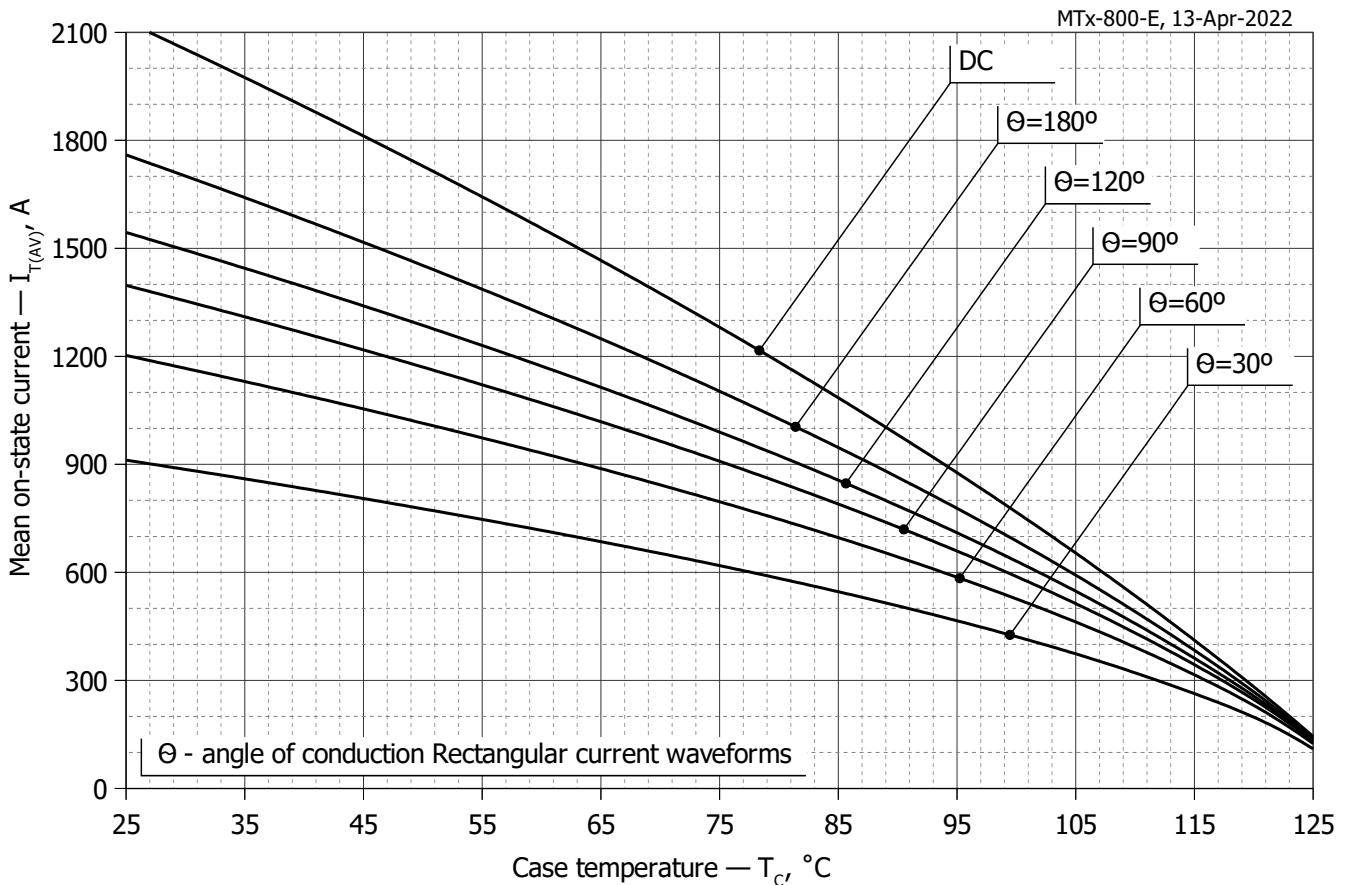
**Fig. 9 - Mean on-state power dissipation  $P_{TAV}$  vs. mean on-state current  $I_{TAV}$  for sinusoidal current waveforms at different conduction angles ( $f=50\text{Hz}$ )**



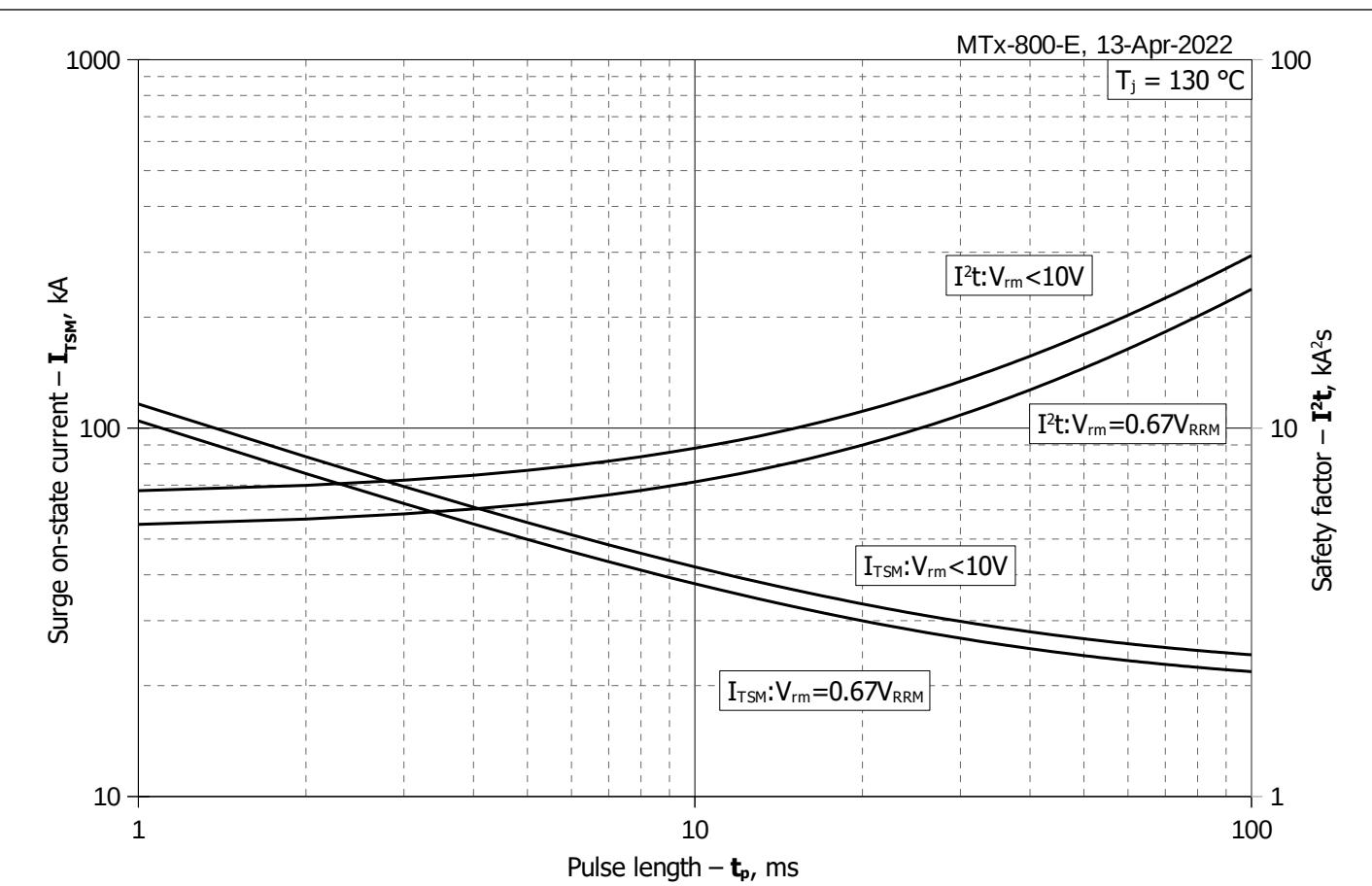
**Fig. 10 – Mean on-state power dissipation  $P_{TAV}$  vs. mean on-state current  $I_{TAV}$  for rectangular current waveforms at different conduction angles and for DC ( $f=50\text{Hz}$ )**



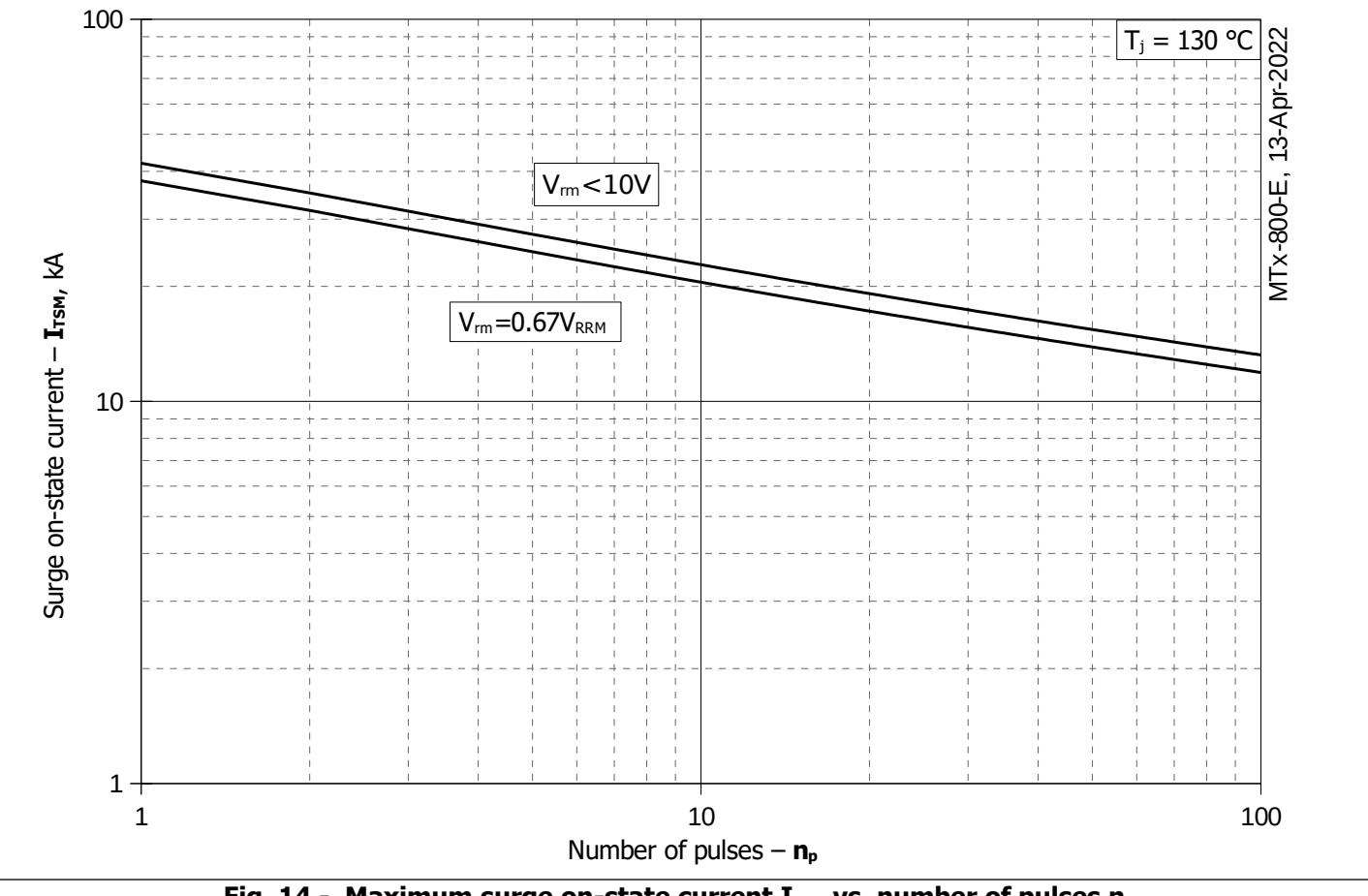
**Fig. 11 – Mean on-state current  $I_{T(AV)}$  vs. case temperature  $T_c$  for sinusoidal current waveforms at different conduction angles ( $f=50\text{Hz}$ )**



**Fig. 12 - Mean on-state current  $I_{T(AV)}$  vs. case temperature  $T_c$  for rectangular current waveforms at different conduction angles and for DC ( $f=50\text{Hz}$ )**



**Fig. 13 – Maximum surge on-state current  $I_{TSM}$  and safety factor  $I^2t$  vs. pulse length  $t_p$**



**Fig. 14 - Maximum surge on-state current  $I_{TSM}$  vs. number of pulses  $n_p$**